Se	arch No	ites

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/770,386	BESSETTE ET AL.	
Examiner	Art Unit	
Patricia Leith	1655	

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Class	Subclass	Date	Examiner
424	725	8/17/2005	PL
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TERFERENCE SEARCHED		
Subclass	· Date	Examiner
725	8/17/2005	PL
	Subclass	Subclass Date

SEARCH NOT (INCLUDING SEARCH S)
	DATE	EXMR
EAST: Interference search & Inventor name search	8/17/2005	PL
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